

| | | | | |
|-----------------------------------|--|-------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/516,331 | CHAE, WAN SHIK | |
| | | Examiner | Art Unit | Page 1 of 1 |
| | | Christine T. Cajilig | 3637 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|-----|--|-----------------|---------------------|----------------|
| * | A | US-4,856,250 A | 08-1989 | Gronau et al. | 52/480 |
| * | B | US-6,364,141 B1 | 04-2002 | Ehrgott, Glenn Alan | 211/189 |
| * | C | US-6,550,206 B2 | 04-2003 | Lee, Chiu-Ying | 52/480 |
| * | D | US-6,564,522 B1 | 05-2003 | Chiu-Ying, Lee | 52/480 |
| * | E | US-6,619,000 B1 | 09-2003 | Chiu-Ying, Lee | 52/127.3 |
| * | F | US-6,857,242 B2 | 02-2005 | He, Jun-Jie | 52/589.1 |
| G | US- | | | | |
| H | US- | | | | |
| I | US- | | | | |
| J | US- | | | | |
| K | US- | | | | |
| L | US- | | | | |
| M | US- | | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.